

Total No. of Questions : 8]

SEAT No. :

PA-744

[Total No. of Pages : 2

[5928]-211

M.E. (E & TC) (VLSI and Embedded Systems)

ASIC DESIGN

(2017 Pattern) (Semester - III) (604202)

Time : 3 Hours]

[Max. Marks : 50

Instructions to the candidates:

- 1) Attempt any 5 questions out of 8.
- 2) Neat diagrams must be drawn whenever necessary.
- 3) Figures to the right indicate full marks.
- 4) Assume suitable data, if necessary.

Q1) a) With neat flow chart explain in detail ASIC Design Flow. **[5]**

b) With neat labeled diagram describe different types of ASIC. **[5]**

Q2) a) Explain VHDL code and test-bench code for D-flip-flop. **[5]**

b) Write short note on logic synthesis and simulation. **[5]**

Q3) a) Differentiate floorplanning and placement in ASIC design. **[4]**

b) How to reuse any ASIC design? Give one example. **[4]**

c) List different CAD tools used in ASIC Design. **[2]**

Q4) a) With neat labeled diagram explain clock distribution technique in ASIC. **[4]**

b) Differentiate global routing and detailed routing. **[4]**

c) Give example of Left-edge algorithm and comment on it. **[2]**

Q5) a) How false path detection is carried out in application specific integrated circuits. **[4]**

b) Write short note on static timing analysis. **[4]**

c) How to estimate logic delays in sequential logic design. **[2]**

P.T.O.

- Q6)** a) Write short note on mixed mode design in ASIC. [4]
b) Describe in brief signal integrity issues in ASIC Design. [4]
c) What are the time related constraints? Explain with one example. [2]
- Q7)** a) Draw and explain linear feedback shift register in detail. [4]
b) Write short note on Joint Test Action Group. [4]
c) Explain basic automatic test pattern generator (ATPG) algorithm for $A'B + BC$. [2]
- Q8)** a) Explain in detail physical faults occurred in ASIC. [4]
b) Write short note on memory testing. [4]
c) Differentiate Scan test Vs Partial test. [2]
